

Search Notes**Application/Control No.**

10/776,278

**Applicant(s)/Patent under
Reexamination**

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Examiner

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Art Unit

1792

SEARCHED

Class	Subclass	Date	Examiner
427	64	6/4/2008	BT
427	67	6/4/2008	BT
427	427.1	6/4/2008	BT
427	427.2	6/4/2008	BT
427	427.6	6/4/2008	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text search using databases in EAST	6/4/2008	BT